

Docket No. 291795US2PCT



MAIL STOP PCT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Janick BIOARRE, et al.

SERIAL NO: 10/580,822

GAU:

FILED: May 26, 2006

EXAMINER:

FOR: METHOD FOR NON-DSTRUCTIVE MEASUREMENT OR COMPARISON OF A LASER RADIATION
CONTENT IN OPTICAL COMPONENTS

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

- ☒ The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

- ☐ Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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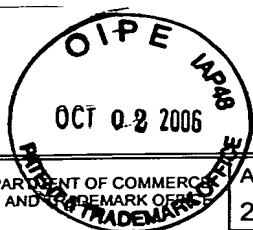
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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

291795US2PCT

SERIAL NO.

10/580,822

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Janick BIGARRE, et al.

FILING DATE

May 26, 2006

GROUP

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO					
	AP					
	AQ					
	AR					
	AS					
	AT					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AV	BIGARRE J. et al., "TRAPPING OF ELECTRICAL CHARGES AND LASER DAMAGE", PROCEEDINGS OF SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 4932, pages 258-267, XP002289327, 2003
	AW	KOZLOWSKI M. R. et al., "LUMINESCENCE INVESTIGATION OF SiO ₂ SURFACES DAMAGED BY 0.35 mm LASER ILLUMINATION", SPIE, vol. 3902, pages 138-144, XP002289328, 2000
	AX	GOLDBERG M. et al., "DOSE EFFECTS OF CATHODOLUMINESCENCE IN SiO ₂ LAYERS ON Si", MATERIALS SCIENCE AND ENGINEERING, vol. B42, pages 293-296, XP002289329, 1996
	AY	STEVENS KALCEFF M. A., "CATHODOLUMINESCENCE MICROCHARACTERIZATION OF THE DEFECT STRUCTURE OF IRRADIATED HYDRATED AND ANHYDROUS FUSED SILICON DIOXIDE", PHYSICAL REVIEW B, vol. 57, pages 5674-5683, XP002289330, 1998
	AZ	REICHLING M., "NANOSECOND UV LASER PULSE INTERACTIONS WITH DIELECTRIC SINGLE CRYSTALS", PROCEEDINGS OF THE SPIE- THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, vol. 3274, pages 2-9, XP002289331, 1998
		<input type="checkbox"/> Additional References sheet(s) attached

Examiner

Date Considered

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.